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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded - Microcontrollers</u>"

Details	
Product Status	Obsolete
Core Processor	RL78
Core Size	16-Bit
Speed	32MHz
Connectivity	CSI, I <sup>2</sup> C, LINbus, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	38
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	5.5K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 12x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	52-LQFP
Supplier Device Package	52-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f104jeafa-v0

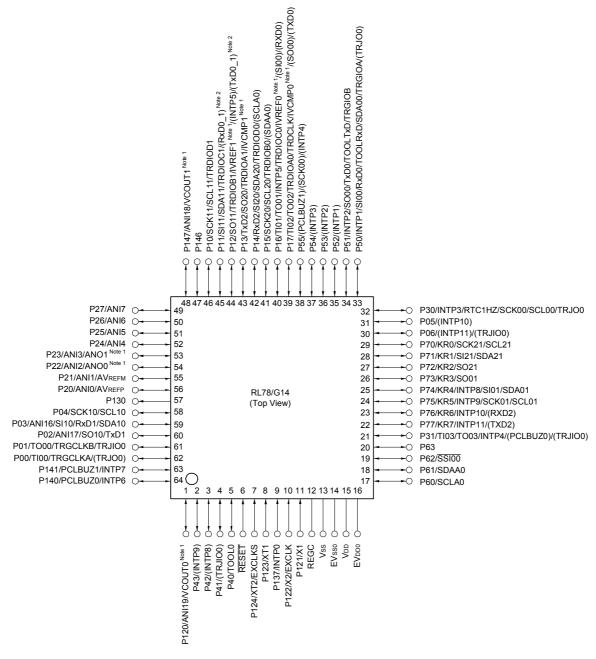
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RL78/G14 1. OUTLINE

### 1.3.8 64-pin products

- 64-pin plastic LQFP (14 × 14 mm, 0.8 mm pitch)
- 64-pin plastic LQFP (12 × 12 mm, 0.65 mm pitch)
- 64-pin plastic LFQFP (10 × 10 mm, 0.5 mm pitch)



- Note 1. Mounted on the 96 KB or more code flash memory products.
- Note 2. Mounted on the 384 KB or more code flash memory products.
- Caution 1. Make EVsso pin the same potential as Vss pin.
- Caution 2. Make VDD pin the potential that is higher than EVDD0 pin.
- Caution 3. Connect the REGC pin to Vss pin via a capacitor (0.47 to 1  $\mu$ F).
- Remark 1. For pin identification, see 1.4 Pin Identification.
- Remark 2. When using the microcontroller for an application where the noise generated inside the microcontroller must be reduced, it is recommended to supply separate powers to the VDD and EVDD0 pins and connect the Vss and EVss0 pins to separate ground lines.
- Remark 3. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register 0, 1 (PIOR0, 1).

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Note

The flash library uses RAM in self-programming and rewriting of the data flash memory.

The target products and start address of the RAM areas used by the flash library are shown below.

R5F104xJ (x = F, G, J, L, M, P): Start address F9F00H

For the RAM areas used by the flash library, see **Self RAM list of Flash Self-Programming Library for RL78 Family (R20UT2944)**.

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(2/2)

			(212)					
		80-pin	100-pin					
lt.	tem	R5F104Mx	R5F104Px					
		(x = F  to  H, J)	(x = F to H, J)					
Clock output/buzz	zer output	2	2					
		(Main system clock: fmain = 20 MHz operation   • 256 Hz, 512 Hz, 1.024 kHz, 2.048 kHz, 4.09	<ul> <li>2.44 kHz, 4.88 kHz, 9.76 kHz, 1.25 MHz, 2.5 MHz, 5 MHz, 10 MHz (Main system clock: fmain = 20 MHz operation)</li> <li>256 Hz, 512 Hz, 1.024 kHz, 2.048 kHz, 4.096 kHz, 8.192 kHz, 16.384 kHz, 32.768 kHz (Subsystem clock: fsub = 32.768 kHz operation)</li> </ul>					
8/10-bit resolution	A/D converter	17 channels	20 channels					
D/A converter		2 channels	2 channels					
Comparator		2 channels	2 channels					
Serial interface		CSI: 2 channels/UART: 1 channel/simplified     CSI: 2 channels/UART: 1 channel/simplified	[80-pin, 100-pin products]  • CSI: 2 channels/UART (UART supporting LIN-bus): 1 channel/simplified I <sup>2</sup> C: 2 channels  • CSI: 2 channels/UART: 1 channel/simplified I <sup>2</sup> C: 2 channels  • CSI: 2 channels/UART: 1 channel/simplified I <sup>2</sup> C: 2 channels  • CSI: 2 channels/UART: 1 channel/simplified I <sup>2</sup> C: 2 channels					
	I <sup>2</sup> C bus	2 channels	2 channels					
Data transfer con	troller (DTC)	39 sources	39 sources					
Event link controller (ELC)		Event input: 26 Event trigger output: 9						
Vectored inter-	Internal	32	32					
rupt sources	External	13	13					
Key interrupt	1	8	8					
Reset		Reset by RESET pin Internal reset by watchdog timer Internal reset by power-on-reset Internal reset by voltage detector Internal reset by illegal instruction execution Internal reset by RAM parity error Internal reset by illegal-memory access	Note					
Power-on-reset circuit		• Power-on-reset: 1.51 ±0.04 V (TA = -40 1.51 ±0.06 V (TA = -40 • Power-down-reset: 1.50 ±0.04 V (TA = -40 1.50 ±0.06 V (TA = -40	to +105°C) to +85°C)					
Voltage detector		1.63 V to 4.06 V (14 stages)						
On-chip debug fu	nction	Provided						
Power supply volt	age	V <sub>DD</sub> = 1.6 to 5.5 V (T <sub>A</sub> = -40 to +85°C) V <sub>DD</sub> = 2.4 to 5.5 V (T <sub>A</sub> = -40 to +105°C)						
Operating ambier	nt temperature	T <sub>A</sub> = -40 to +85°C (A: Consumer applications, D: Industrial applications), T <sub>A</sub> = -40 to +105°C (G: Industrial applications)						

**Note** The illegal instruction is generated when instruction code FFH is executed.

Reset by the illegal instruction execution is not issued by emulation with the in-circuit emulator or on-chip debug emulator.

# (4) During communication at same potential (CSI mode) (slave mode, SCKp... external clock input) (TA = -40 to +85°C, 1.6 V $\leq$ EVDD0 = EVDD1 $\leq$ VDD $\leq$ 5.5 V, VSS = EVSS0 = EVSS1 = 0 V)

Parameter	Symbol	Cond	ditions	HS (high-spee	d main)	LS (low-speed mode	d main)	LV (low-voltag mode	e main)	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle	tkcy2	4.0 V ≤ EVDD0 ≤ 5.5 V	20 MHz < fmck	8/fмск		_		_		ns
time Note 5			fмcк ≤ 20 MHz	6/fмск		6/fмск		6/fмск		ns
		2.7 V ≤ EVDD0 ≤ 5.5 V	16 MHz < fmck	8/fмск		_		_		ns
			fмcк ≤ 16 MHz	6/fмск		6/fмск		6/fмск		ns
		2.4 V ≤ EVDD0 ≤ 5.5 V		6/fмск and 500		6/fмск and 500		6/fмск and 500		ns
		1.8 V ≤ EVDD0 ≤ 5.5 V		6/fмск and 750		6/fмск and 750		6/fмск and 750		ns
		1.7 V ≤ EV <sub>DD0</sub> ≤ 5.5 V		6/fмск and 1500		6/fмск and 1500		6/fмск and 1500		ns
		1.6 V ≤ EV <sub>DD0</sub> ≤ 5.5 V		_		6/fмск and 1500		6/fмск and 1500		ns
SCKp high-/	tĸн2,	4.0 V ≤ EVDD0 ≤ 5.5 V		tkcy2/2 - 7		tkcy2/2 - 7		tkcy2/2 - 7		ns
low-level width	tKL2	2.7 V ≤ EV <sub>DD0</sub> ≤ 5.5 V		tkcy2/2 - 8		tkcy2/2 - 8		tkcy2/2 - 8		ns
		1.8 V ≤ EVDD0 ≤ 5.5 V		tkcy2/2 - 18		tkcy2/2 - 18		tkcy2/2 - 18		ns
		1.7 V ≤ EV <sub>DD0</sub> ≤ 5.5 V		tkcy2/2 - 66		tkcy2/2 - 66		tkcy2/2 - 66		ns
		1.6 V ≤ EVDD0 ≤ 5.5 V		_		tkcy2/2 - 66		tkcy2/2 - 66		ns
SIp setup time	tsık2	2.7 V ≤ EVDD0 ≤ 5.5 V		1/fмск + 20		1/fмск + 30		1/fмск + 30		ns
(to SCKp↑) Note 1		1.8 V ≤ EVDD0 ≤ 5.5 V		1/fмск + 30		1/fмск + 30		1/fмск + 30		ns
		1.7 V ≤ EVDD0 ≤ 5.5 V		1/fмск + 40		1/fмск + 40		1/fмск + 40		ns
		1.6 V ≤ EVDD0 ≤ 5.5 V		_		1/fмск + 40		1/fмск + 40		ns
SIp hold time	tks12	1.8 V ≤ EVDD0 ≤ 5.5 V		1/fмск + 31		1/fмск + 31		1/fмск + 31		ns
(from SCKp↑) Note 2		1.7 V ≤ EV <sub>DD0</sub> ≤ 5.5 V		1/fмск + 250		1/fмск + 250		1/fмск + 250		ns
		1.6 V ≤ EVDD0 ≤ 5.5 V		_		1/fмск + 250		1/fмск + 250		ns
Delay time from SCKp↓ to	tkso2	C = 30 pF Note 4	2.7 V ≤ EV <sub>DD0</sub> ≤ 5.5 V		2/fмск + 44		2/fмск + 110		2/fмск + 110	ns
SOp output Note 3			2.4 V ≤ EV <sub>DD0</sub> ≤ 5.5 V		2/fмск + 75		2/fмск + 110		2/fмск + 110	ns
			1.8 V ≤ EV <sub>DD0</sub> ≤ 5.5 V		2/fмcк + 100		2/fмск + 110		2/fмск + 110	ns
			1.7 V ≤ EV <sub>DD0</sub> ≤ 5.5 V		2/fмcк + 220		2/fмск + 220		2/fмск + 220	ns
		_	1.6 V ≤ EV <sub>DD0</sub> ≤ 5.5 V		_		2/fмск + 220		2/fмcк + 220	ns

- Note 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Note 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Note 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Note 4. C is the load capacitance of the SOp output lines.
- **Note 5.** The maximum transfer rate when using the SNOOZE mode is 1 Mbps.
- Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).



### (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode)

(TA = -40 to +85°C, 1.6 V  $\leq$  EVDD0 = EVDD1  $\leq$  VDD  $\leq$  5.5 V, VSS = EVSS0 = EVSS1 = 0 V)

Parameter	Symbol	Conditions		٠ ٠	-speed main) node	,	speed main) node	,	voltage main) mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate		reception	$4.0 \text{ V} \le \text{EV}_{DD0} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V}$		f <sub>MCK</sub> /6 Note 1		f <sub>MCK</sub> /6 Note 1		f <sub>MCK</sub> /6 Note 1	bps
			Theoretical value of the maximum transfer rate fmck = fclk Note 4		5.3		1.3		0.6	Mbps
			$2.7 \text{ V} \le \text{EV}_{\text{DD0}} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_{\text{b}} \le 2.7 \text{ V}$		f <sub>MCK</sub> /6 Note 1		f <sub>MCK</sub> /6 Note 1		f <sub>MCK</sub> /6 Note 1	bps
			Theoretical value of the maximum transfer rate folk Note 4		5.3		1.3		0.6	Mbps
			$1.8 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V},$ $1.6 \text{ V} \le \text{V}_{\text{b}} \le 2.0 \text{ V}$		fмск/6 Notes 1, 2, 3		fмск/6 Notes 1, 2		fмск/6 Notes 1, 2	bps
			Theoretical value of the maximum transfer rate fMCK = fCLK Note 4		5.3		1.3		0.6	Mbps

Note 1. Transfer rate in the SNOOZE mode is 4800 bps only.

However, the SNOOZE mode cannot be used when FRQSEL4 = 1.

Note 2. Use it with  $EVDD0 \ge V_b$ .

Note 3. The following conditions are required for low voltage interface when EVDDO < VDD.

 $2.4~V \leq EV_{DD0} < 2.7~V;$  MAX. 2.6~Mbps

 $1.8 \text{ V} \leq \text{EV}_{\text{DD0}} < 2.4 \text{ V}$ : MAX. 1.3 Mbps

**Note 4.** The maximum operating frequencies of the CPU/peripheral hardware clock (fcLK) are:

HS (high-speed main) mode: 32 MHz ( $2.7 \text{ V} \le \text{VdD} \le 5.5 \text{ V}$ )

16 MHz (2.4 V  $\leq$  VDD  $\leq$  5.5 V)

LS (low-speed main) mode: 8 MHz (1.8 V  $\leq$  VDD  $\leq$  5.5 V) LV (low-voltage main) mode: 4 MHz (1.6 V  $\leq$  VDD  $\leq$  5.5 V)

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance (for the 30- to 52-pin products)/EVDD tolerance (for the 64- to 100-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Remark 1. Vb [V]: Communication line voltage

**Remark 2.** q: UART number (q = 0 to 3), g: PIM and POM number (g = 0, 1, 5, 14)

Remark 3. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,

n: Channel number (mn = 00 to 03, 10 to 13)

Remark 4. UART2 cannot communicate at different potential when bit 1 (PIOR01) of peripheral I/O redirection register 0 (PIOR0) is

# (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output)

(TA = -40 to +85°C, 1.8 V  $\leq$  EVDD0 = EVDD1  $\leq$  VDD  $\leq$  5.5 V, VSS = EVSS0 = EVSS1 = 0 V)

Parameter	Symbol		Conditions	HS (high-s main) mo		LS (low-speed mode	,	LV (low-vo main) mo	•	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	tkcy1 ≥ 4/fclk	$ \begin{aligned} 4.0 \ V &\leq EV_{DD0} \leq 5.5 \ V, \\ 2.7 \ V &\leq V_b \leq 4.0 \ V, \\ C_b &= 30 \ pF, \ R_b = 1.4 \ k\Omega \end{aligned} $	300		1150		1150		ns
			$ \begin{aligned} 2.7 & \ V \leq EV_{DDO} < 4.0 \ V, \\ 2.3 & \ V \leq V_b \leq 2.7 \ V, \\ C_b & = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{aligned} $	500		1150		1150		ns
			$ \begin{aligned} &1.8 \text{ V} \leq \text{EV}_{\text{DDO}} < 3.3 \text{ V}, \\ &1.6 \text{ V} \leq \text{V}_{\text{b}} \leq 2.0 \text{ V Note}, \\ &C_{\text{b}} = 30 \text{ pF},  R_{\text{b}} = 5.5 \text{ k}\Omega \end{aligned} $	1150		1150		1150		ns
SCKp high-level tкн1 width		$ 4.0 \text{ V} \leq \text{EV}_{DD0} \leq 5.5 \text{ V}, \\ 2.7 \text{ V} \leq \text{V}_{b} \leq 4.0 \text{ V}, \\ C_{b} = 30 \text{ pF}, R_{b} = 1.4 \text{ k}\Omega $		tксү1/2 - 75		tксү1/2 - 75		tксү1/2 - 75		ns
		$2.7 \text{ V} \le \text{EV}_{\text{DD0}}$ $2.3 \text{ V} \le \text{V}_{\text{b}} \le 2$ $C_{\text{b}} = 30 \text{ pF}, \text{ Rb}$	tkcy1/2 - 170		tксү1/2 - 170		tксу1/2 - 170		ns	
		1.8 V $\leq$ EV <sub>DD0</sub> $<$ 3.3 V, 1.6 V $\leq$ V <sub>b</sub> $\leq$ 2.0 V Note, C <sub>b</sub> = 30 pF, R <sub>b</sub> = 5.5 kΩ		tkcy1/2 - 458		tkcy1/2 - 458		tkcy1/2 - 458		ns
SCKp low-level width	tKL1	$4.0 \text{ V} \le \text{EVDD0}$ $2.7 \text{ V} \le \text{Vb} \le 4$ $C_b = 30 \text{ pF}, \text{ Rb}$	0 V,	tксү1/2 - 12		tkcy1/2 - 50		tксү1/2 - 50		ns
	$2.7 \ V \le EVDI$ $2.3 \ V \le V_b \le C_b = 30 \ pF, I$ $1.8 \ V \le EVDI$ $1.6 \ V \le V_b \le C_b = 30 \ pF, I$		7 V,	tксү1/2 - 18		tkcy1/2 - 50		tксү1/2 - 50		ns
			0 V Note,	tkcy1/2 - 50		tксү1/2 - 50		tксү1/2 - 50		ns

Note Use it with  $EVDD0 \ge V_b$ .

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (for the 30- to 52-pin products)/EVDD tolerance (for the 64- to 100-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

(Remarks are listed two pages after the next page.)

# (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output)

 $(TA = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$  (3/3)

Parameter	Symbol	Conditions		speed main) ode	,	peed main) ode	,	ltage main) ode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SIp setup time (to SCKp↓) Note 1	tsıĸ1	$ \begin{aligned} 4.0 \ V &\leq EV_{DD0} \leq 5.5 \ V, \\ 2.7 \ V &\leq V_b \leq 4.0 \ V, \\ C_b &= 30 \ pF, \ R_b = 1.4 \ k\Omega \end{aligned} $	44		110		110		ns
		$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} < 4.0 \text{ V}, \\ 2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ \text{Cb} = 30 \text{ pF}, \text{Rb} = 2.7 \text{ k}\Omega $	44		110		110		ns
		$\begin{array}{l} 1.8 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V}, \\ 1.6 \text{ V} \leq \text{V}_{\text{b}} \leq 2.0 \text{ V} \text{ Note 2}, \\ \text{C}_{\text{b}} = 30 \text{ pF}, \text{R}_{\text{b}} = 5.5 \text{ k}\Omega \end{array}$	110		110		110		ns
SIp hold time (from SCKp↓) Note 1	tksi1	$ \begin{aligned} &4.0 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}, \\ &2.7 \text{ V} \leq \text{V}_{\text{b}} \leq 4.0 \text{ V}, \\ &\text{Cb} = 30 \text{ pF}, \text{ Rb} = 1.4 \text{ k}\Omega \end{aligned} $	19		19		19		ns
		$ \begin{aligned} 2.7 & \text{ V} \leq \text{EV}_{\text{DD0}} < 4.0 \text{ V}, \\ 2.3 & \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ \text{Cb} & = 30 \text{ pF}, \text{ Rb} = 2.7 \text{ k}\Omega \end{aligned} $	19		19		19		ns
		$\begin{split} 1.8 \ V &\leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V \ ^{\text{Note 2}}, \\ C_b &= 30 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$	19		19		19		ns
Delay time from SCKp↑ to SOp output Note 1	tkso1	$ \begin{aligned} 4.0 & \ V \le EV_{DD0} \le 5.5 \ V, \\ 2.7 & \ V \le V_b \le 4.0 \ V, \\ C_b & = 30 \ pF, \ R_b = 1.4 \ k\Omega \end{aligned} $		25		25		25	ns
		$\label{eq:controller} \begin{split} 2.7 \ & V \leq EV_{DD0} < 4.0 \ V, \\ 2.3 \ & V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$		25		25		25	ns
		$\begin{array}{c} 1.8 \; \text{V} \leq \text{EV}_{\text{DD0}} < 3.3 \; \text{V}, \\ 1.6 \; \text{V} \leq \text{V}_{\text{b}} \leq 2.0 \; \text{V} \; \text{Note 2}, \\ \text{Cb} = 30 \; \text{pF}, \; \text{Rb} = 5.5 \; \text{k}\Omega \end{array}$		25		25		25	ns

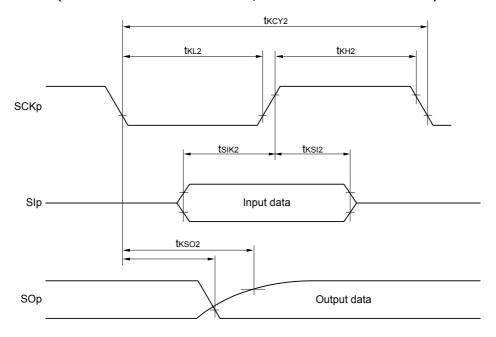
Note 1. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (for the 30- to 52-pin products)/EVDD tolerance (for the 64- to 100-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

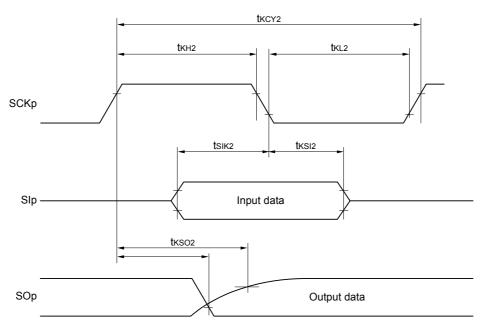
(Remarks are listed on the next page.)

Note 2. Use it with  $EVDD0 \ge V_b$ .

## CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



## CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remark 1. p: CSI number (p = 00, 01, 10, 20, 30, 31), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM and POM number (g = 0, 1, 3 to 5, 14)

Remark 2. CSI01 of 48-, 52-, 64-pin products, and CSI11 and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

Also, communication at different potential cannot be performed during clock synchronous serial communication with the slave select function.

(4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI0, ANI2 to ANI14, ANI16 to ANI20

(TA = -40 to +85°C, 2.4 V  $\leq$  VDD  $\leq$  5.5 V, 1.6 V  $\leq$  EVDD = EVDD1  $\leq$  VDD, Vss = EVss0 = EVss1 = 0 V, Reference voltage (+) = VBGR Note 3, Reference voltage (-) = AVREFM = 0 V Note 4, HS (high-speed main) mode)

Parameter	Symbol	Co	MIN.	TYP.	MAX.	Unit	
Resolution	RES				8		bit
Conversion time	tconv	8-bit resolution	$2.4 \text{ V} \le \text{Vdd} \le 5.5 \text{ V}$	17		39	μs
Zero-scale error Notes 1, 2	Ezs	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±0.60	% FSR
Integral linearity error Note 1	ILE	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±1.0	LSB
Analog input voltage	Vain			0		V <sub>BGR</sub> Note 3	V

Note 1. Excludes quantization error (±1/2 LSB).

Note 2. This value is indicated as a ratio (% FSR) to the full-scale value.

Note 3. Refer to 2.6.2 Temperature sensor characteristics/internal reference voltage characteristic.

**Note 4.** When reference voltage (-) = Vss, the MAX. values are as follows.

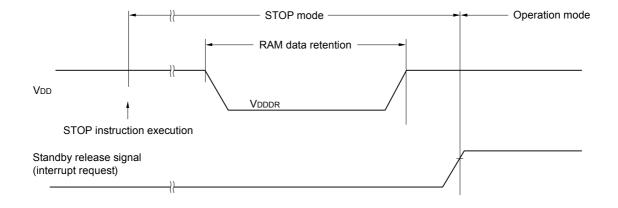
Zero-scale error: Add  $\pm 0.35\%$ FSR to the MAX. value when reference voltage (-) = AVREFM. Integral linearity error: Add  $\pm 0.5$  LSB to the MAX. value when reference voltage (-) = AVREFM. Differential linearity error: Add  $\pm 0.2$  LSB to the MAX. value when reference voltage (-) = AVREFM.

### 2.7 RAM Data Retention Characteristics

#### $(TA = -40 \text{ to } +85^{\circ}C, Vss = 0V)$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.46 Note		5.5	V

**Note** The value depends on the POR detection voltage. When the voltage drops, the RAM data is retained before a POR reset is effected, but RAM data is not retained when a POR reset is effected.



### 2.8 Flash Memory Programming Characteristics

### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{VDD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
System clock frequency	fclk	1.8 V ≤ VDD ≤ 5.5 V	1		32	MHz
Number of code flash rewrites Notes 1, 2, 3	Cerwr	Retained for 20 years TA = 85°C	1,000			Times
Number of data flash rewrites Notes 1, 2, 3		Retained for 1 year TA = 25°C		1,000,000		
		Retained for 5 years TA = 85°C	100,000			
		Retained for 20 years TA = 85°C	10,000			

Note 1. 1 erase + 1 write after the erase is regarded as 1 rewrite. The retaining years are until next rewrite after the rewrite.

## 2.9 Dedicated Flash Memory Programmer Communication (UART)

### (TA = -40 to +85°C, 1.8 V $\leq$ EVDD0 = EVDD1 $\leq$ VDD $\leq$ 5.5 V, Vss = EVss0 = EVss1 = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During serial programming	115,200		1,000,000	bps

Note 2. When using flash memory programmer and Renesas Electronics self-programming library

**Note 3.** These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.

- Note 1. Total current flowing into VDD and EVDD0, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD0 or Vss, EVss0. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing data flash rewrite.
- Note 2. When high-speed on-chip oscillator and subsystem clock are stopped.
- **Note 3.** When high-speed system clock and subsystem clock are stopped.
- Note 4. When high-speed on-chip oscillator and high-speed system clock are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation). However, not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.
- Note 5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below. HS (high-speed main) mode:  $2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}_{\textcircled{Q}}1 \text{ MHz}$  to 32 MHz  $2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}_{\textcircled{Q}}1 \text{ MHz}$  to 16 MHz
- Remark 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
- Remark 2. fHoco: High-speed on-chip oscillator clock frequency (64 MHz max.)

  Remark 3. fil: High-speed on-chip oscillator clock frequency (32 MHz max.)

  Remark 4. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
- Remark 5. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C

- Note 1. Total current flowing into VDD, EVDD0, and EVDD1, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD0, and EVDD1, or Vss, EVss0, and EVss1. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, D/A converter, comparator, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
- Note 2. During HALT instruction execution by flash memory.
- Note 3. When high-speed on-chip oscillator and subsystem clock are stopped.
- Note 4. When high-speed system clock and subsystem clock are stopped.
- Note 5. When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1). The current flowing into the RTC is included. However, not including the current flowing into the 12-bit interval timer and watchdog timer.
- Note 6. Not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.
- **Note 7.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode:  $2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V} @ 1 \text{ MHz to } 32 \text{ MHz}$ 

 $2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V} @1 \text{ MHz to } 16 \text{ MHz}$ 

- Note 8. Regarding the value for current to operate the subsystem clock in STOP mode, refer to that in HALT mode.
- Remark 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
- Remark 2. fHoco: High-speed on-chip oscillator clock frequency (64 MHz max.)
- Remark 3. fil: High-speed on-chip oscillator clock frequency (32 MHz max.)
- Remark 4. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
- Remark 5. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is TA = 25°C

## (2) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output) (TA = -40 to +105°C, 2.4 V $\leq$ EVDD0 = EVDD1 $\leq$ VDD $\leq$ 5.5 V, Vss = EVss0 = EVss1 = 0 V)

•		· · · · · · · · · · · · · · · · · · ·				
Parameter	Symbol Conditions		HS (high-sր mo		Unit	
				MIN.	MAX.	
SCKp cycle time	tkcy1	tkcy1 ≥ 4/fclk	2.7 V ≤ EVDD0 ≤ 5.5 V	250		ns
			2.4 V ≤ EV <sub>DD0</sub> ≤ 5.5 V	500		ns
SCKp high-/low-level width	tkH1, tkL1	4.0 V ≤ EVDD0 ≤ 5.5 V		tксү1/2 - 24		ns
		2.7 V ≤ EVDD0 :	2.7 V ≤ EV <sub>DD0</sub> ≤ 5.5 V			ns
		2.4 V ≤ EV <sub>DD0</sub> :	2.4 V ≤ EVDD0 ≤ 5.5 V			ns
SIp setup time (to SCKp↑) Note 1	tsıĸ1	4.0 V ≤ EV <sub>DD0</sub> :	4.0 V ≤ EV <sub>DD0</sub> ≤ 5.5 V			ns
		2.7 V ≤ EV <sub>DD0</sub> :	2.7 V ≤ EV <sub>DD0</sub> ≤ 5.5 V			ns
		2.4 V ≤ EVDD0 :	2.4 V ≤ EV <sub>DD0</sub> ≤ 5.5 V			ns
SIp hold time (from SCKp↑) Note 2	tksıı			38		ns
Delay time from SCKp↓ to SOp output Note 3	tkso1	C = 30 pF Note	C = 30 pF Note 4		50	ns
	- 1	-1				

- Note 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Note 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Note 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Note 4. C is the load capacitance of the SCKp and SOp output lines.
- Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).
- **Remark 1.** p: CSI number (p = 00, 01, 10, 11, 20, 21, 30, 31), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM number (g = 0, 1, 3 to 5, 14)
- Remark 2. fmck: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))

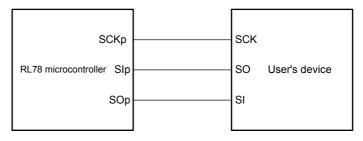
# (3) During communication at same potential (CSI mode) (slave mode, SCKp... external clock input) (TA = -40 to +105°C, 2.4 V $\leq$ EVDD0 = EVDD1 $\leq$ VDD $\leq$ 5.5 V, Vss = EVss0 = EVss1 = 0 V) (2/2)

Parameter	Symbol	Conc	litions	HS (high-spee	d main) mode	Unit
					MAX.	
SSI00 setup time	tssik	DAPmn = 0	2.7 V ≤ EV <sub>DD0</sub> ≤ 5.5 V	240		ns
			2.4 V ≤ EVDD0 ≤ 5.5 V	400		ns
		DAPmn = 1	2.7 V ≤ EVDD0 ≤ 5.5 V	1/fмск + 240		ns
			2.4 V ≤ EVDD0 ≤ 5.5 V	1/fмск + 400		ns
SSI00 hold time	tĸssı	DAPmn = 0	2.7 V ≤ EVDD0 ≤ 5.5 V	1/fмск + 240		ns
			2.4 V ≤ EVDD0 ≤ 5.5 V	1/fмск + 400		ns
		DAPmn = 1	2.7 V ≤ EVDD0 ≤ 5.5 V	240		ns
			2.4 V ≤ EV <sub>DD0</sub> ≤ 5.5 V	400		ns

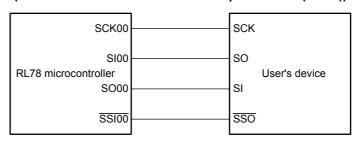
Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remark p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM number (g = 3, 5)

#### CSI mode connection diagram (during communication at same potential)



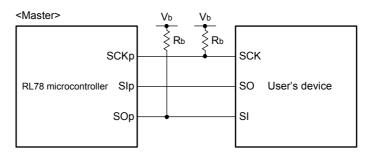
# CSI mode connection diagram (during communication at same potential) (Slave Transmission of slave select input function (CSI00))



**Remark 1.** p: CSI number (p = 00, 01, 10, 11, 20, 21, 30, 31)

Remark 2. m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13)

#### CSI mode connection diagram (during communication at different potential



- **Remark 5.** Rb[ $\Omega$ ]: Communication line (SCKp, SOp) pull-up resistance, Cb[F]: Communication line (SCKp, SOp) load capacitance, Vb[V]: Communication line voltage
- **Remark 6.** p: CSI number (p = 00, 01, 10, 20, 30, 31), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM and POM number (g = 0, 1, 3 to 5, 14)
- Remark 7. fmck: Serial array unit operation clock frequency
  (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,
  n: Channel number (mn = 00))
- Remark 8. CSI01 of 48-, 52-, 64-pin products, and CSI11 and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

### 3.5.2 Serial interface IICA

(TA = -40 to +105°C, 2.4 V  $\leq$  EVDD0 = EVDD1  $\leq$  VDD  $\leq$  5.5 V, VSS = EVSS0 = EVSS1 = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) mode		mode	Unit	
			Standar	d mode	Fast	mode	
			MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fscL	Fast mode: fclk ≥ 3.5 MHz	_	_	0	400	kHz
		Standard mode: fclk ≥ 1 MHz	0	100	_	_	kHz
Setup time of restart condition	tsu: sta		4.7		0.6		μs
Hold time Note 1	thd: sta		4.0		0.6		μs
Hold time when SCLA0 = "L"	tLOW		4.7		1.3		μs
Hold time when SCLA0 = "H"	tніgн		4.0		0.6		μs
Data setup time (reception)	tsu: dat		250		100		ns
Data hold time (transmission) Note 2	thd: dat		0	3.45	0	0.9	μs
Setup time of stop condition	tsu: sto		4.0		0.6		μs
Bus-free time	tbuf		4.7		1.3		μs

**Note 1.** The first clock pulse is generated after this period when the start/restart condition is detected.

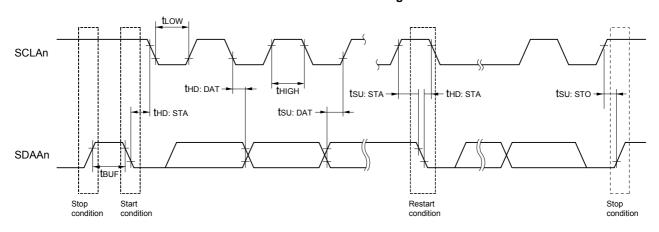
Note 2. The maximum value (MAX.) of thd: DAT is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.

Caution The values in the above table are applied even when bit 2 (PIOR02) in the peripheral I/O redirection register 0 (PIOR0) is 1. At this time, the pin characteristics (IOH1, IOL1, VOH1, VOL1) must satisfy the values in the redirect destination.

Remark The maximum value of C<sub>b</sub> (communication line capacitance) and the value of R<sub>b</sub> (communication line pull-up resistor) at that time in each mode are as follows.

Standard mode:  $C_b$  = 400 pF,  $R_b$  = 2.7 k $\Omega$ Fast mode:  $C_b$  = 320 pF,  $R_b$  = 1.1 k $\Omega$ 

### IICA serial transfer timing



Remark n = 0, 1

(2) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI16 to ANI20

(TA = -40 to +105°C, 2.4 V  $\leq$  EVDD0 = EVDD1  $\leq$  VDD  $\leq$  5.5 V, 2.4 V  $\leq$  AVREFP  $\leq$  VDD  $\leq$  5.5 V, VSS = EVSS1 = 0 V, Reference voltage (+) = AVREFP, Reference voltage (-) = AVREFM = 0 V)

Parameter	Symbol	Cond	itions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error Note 1	AINL	10-bit resolution EV <sub>DD0</sub> ≤ AV <sub>REFP</sub> = V <sub>DD</sub> Notes 3, 4	2.4 V ≤ AVREFP ≤ 5.5 V		1.2	±5.0	LSB
Conversion time	tconv	10-bit resolution	$3.6 \text{ V} \leq \text{Vdd} \leq 5.5 \text{ V}$	2.125		39	μs
		Target ANI pin: ANI16 to ANI20	$2.7 \text{ V} \leq \text{Vdd} \leq 5.5 \text{ V}$	3.1875		39	μs
			$2.4~\text{V} \leq \text{V}_{\text{DD}} \leq 5.5~\text{V}$	17		39	μs
Zero-scale error Notes 1, 2	Ezs	10-bit resolution EV <sub>DD0</sub> ≤ AV <sub>REFP</sub> = V <sub>DD</sub> Notes 3, 4	2.4 V ≤ AVREFP ≤ 5.5 V			±0.35	%FSR
Full-scale error Notes 1, 2	Ers	10-bit resolution EV <sub>DD0</sub> ≤ AV <sub>REFP</sub> = V <sub>DD</sub> Notes 3, 4	2.4 V ≤ AVREFP ≤ 5.5 V			±0.35	%FSR
Integral linearity error Note 1	ILE	10-bit resolution EV <sub>DD0</sub> ≤ AV <sub>REFP</sub> = V <sub>DD</sub> Notes 3, 4	2.4 V ≤ AVREFP ≤ 5.5 V			±3.5	LSB
Differential linearity error Note 1	DLE	10-bit resolution EV <sub>DD0</sub> ≤ AV <sub>REFP</sub> = V <sub>DD</sub> Notes 3, 4	2.4 V ≤ AVREFP ≤ 5.5 V			±2.0	LSB
Analog input voltage	Vain	ANI16 to ANI20		0		AVREFP and EVDD0	V

Note 1. Excludes quantization error (±1/2 LSB).

Note 2. This value is indicated as a ratio (%FSR) to the full-scale value.

**Note 3.** When  $EVDD0 \le AVREFP \le VDD$ , the MAX. values are as follows.

Overall error: Add  $\pm 1.0$  LSB to the MAX. value when AVREFP = VDD. Zero-scale error/Full-scale error: Add  $\pm 0.05\%$ FSR to the MAX. value when AVREFP = VDD. Integral linearity error/ Differential linearity error: Add  $\pm 0.5$  LSB to the MAX. value when AVREFP = VDD.

Note 4. When  $AV_{REFP} < EV_{DD0} \le V_{DD}$ , the MAX. values are as follows.

Overall error: Add  $\pm 4.0$  LSB to the MAX. value when AVREFP = VDD. Zero-scale error/Full-scale error: Add  $\pm 0.20\%$ FSR to the MAX. value when AVREFP = VDD. Integral linearity error/ Differential linearity error: Add  $\pm 2.0$  LSB to the MAX. value when AVREFP = VDD.

(3) When reference voltage (+) = VDD (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = Vss (ADREFM = 0), target pin: ANI0 to ANI14, ANI16 to ANI20, internal reference voltage, and temperature sensor output voltage

(TA = -40 to +105°C, 2.4 V  $\leq$  EVDD0 = EVDD1  $\leq$  VDD  $\leq$  5.5 V, Vss = EVss0 = EVss1 = 0 V, Reference voltage (+) = VDD, Reference voltage (-) = Vss)

Parameter	Symbol	Conditions	Conditions		TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error Note 1	AINL	10-bit resolution	2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V		1.2	±7.0	LSB
Conversion time	tconv	10-bit resolution	3.6 V ≤ V <sub>DD</sub> ≤ 5.5 V	2.125		39	μs
		Target pin: ANI0 to ANI14, ANI16 to ANI20	$2.7 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	3.1875		39	μs
			2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V	17		39	μs
		10-bit resolution	$3.6 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	2.375		39	μs
		Target pin: internal reference voltage, and temperature sensor output voltage	$2.7 \text{ V} \le \text{Vdd} \le 5.5 \text{ V}$	3.5625		39	μs
		(HS (high-speed main) mode)	$2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}$	17		39	μs
Zero-scale error Notes 1, 2	Ezs	10-bit resolution	2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V			±0.60	%FSR
Full-scale error Notes 1, 2	Ers	10-bit resolution	2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V			±0.60	%FSR
Integral linearity error Note 1	ILE	10-bit resolution	2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V			±4.0	LSB
Differential linearity error Note 1	DLE	10-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±2.0	LSB
Analog input voltage	Analog input voltage Vain ANI0 to ANI14		-	0		VDD	V
		ANI16 to ANI20		0		EV <sub>DD0</sub>	٧
		Internal reference voltage (2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V, HS (high-speed main) mode)		\	V <sub>BGR</sub> Note 3		V
		Temperature sensor output voltage (2.4 V $\leq$ VDD $\leq$ 5.5 V, HS (high-speed main) mode)			V <sub>TMPS25</sub> Note 3		V

Note 1. Excludes quantization error (±1/2 LSB).

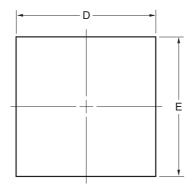
Note 2. This value is indicated as a ratio (% FSR) to the full-scale value.

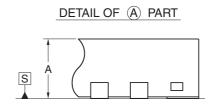
Note 3. Refer to 3.6.2 Temperature sensor characteristics/internal reference voltage characteristic.

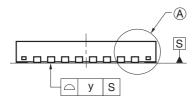
## 4.2 32-pin products

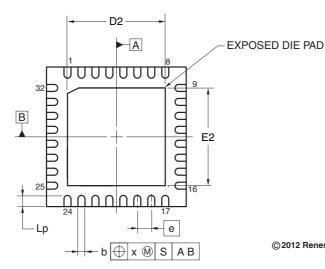
R5F104BAANA, R5F104BCANA, R5F104BDANA, R5F104BEANA, R5F104BFANA, R5F104BGANA R5F104BADNA, R5F104BCDNA, R5F104BDNA, R5F104BEDNA, R5F104BFDNA, R5F104BGDNA R5F104BAGNA, R5F104BCGNA, R5F104BDGNA, R5F104BEGNA, R5F104BGNA, R5F104BGNA

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-HWQFN32-5x5-0.50	PWQN0032KB-A	P32K8-50-3B4-4	0.06









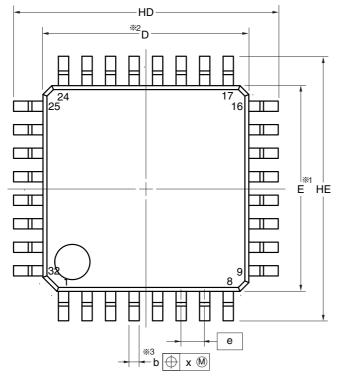
Referance Symbol	Dimension in Millimeters						
	Min	Nom	Max				
D	4.95	5.00	5.05				
Е	4.95	5.00	5.05				
Α	0.70	0.75	0.80				
b	0.18	0.25	0.30				
е		0.50	_				
Lp	0.30	0.40	0.50				
х			0.05				
у	_	_	0.05				

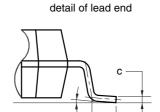
ITEM			D2			E2	
		MIN	NOM	MAX	MIN	MOM	MAX
EXPOSED DIE PAD VARIATIONS	Α	3.45	3.50	3.55	3.45	3.50	3.55

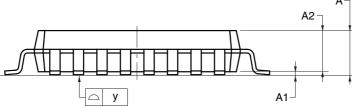
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R5F104BAAFP, R5F104BCAFP, R5F104BDAFP, R5F104BEAFP, R5F104BFAFP, R5F104BGAFP R5F104BADFP, R5F104BCDFP, R5F104BDDFP, R5F104BEDFP, R5F104BFDFP, R5F104BGDFP R5F104BAGFP, R5F104BCGFP, R5F104BDGFP, R5F104BEGFP, R5F104BFGFP, R5F104BGGFP

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LQFP32-7x7-0.80	PLQP0032GB-A	P32GA-80-GBT-1	0.2







(UNIT:mm)

	( -
ITEM	DIMENSIONS
D	7.00±0.10
Е	7.00±0.10
HD	9.00±0.20
HE	9.00±0.20
Α	1.70 MAX.
A1	0.10±0.10
A2	1.40
b	$0.37{\pm}0.05$
С	$0.145 \pm 0.055$
L	0.50±0.20
θ	0° to 8°
е	0.80
х	0.20
v	0.10

#### NOTE

- 1. Dimensions "%1" and "%2" do not include mold flash.
- 2.Dimension "%3" does not include trim offset.

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